

# New Jersey Semi-Conductor Products, Inc.

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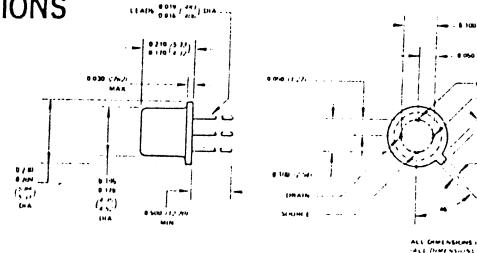
2N5397

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## N-CHANNEL SILICON JUNCTION FIELD-EFFECT TRANSISTOR

FOR UHF AMPLIFIER, MIXER AND OSCILLATOR APPLICATIONS  
AND VIDEO AMPLIFIER APPLICATIONS

- $G_{ps} = 10 \text{ dB}$  Typical (Common Gate) at 450 MHz (2N5397)
- NF = 3 dB Typical at 450 MHz
- $C_{rss} = 1 \text{ pF}$  Typical



TO-72

Fourth lead is in electrical contact with case.

### PRODUCT CONDITIONING

Units receive the following treatment before final electrical tests:

High Temp Storage: 24 Hours at 150°C      25,000g Acceleration/Impact in the Y<sub>1</sub> Plane  
Thermal Shock: +100 to 0°C for 5 Cycles      Helium and/or Gross Leak Tests for Hermetic

### \*ABSOLUTE MAXIMUM RATINGS (25°C)

Gate-Drain or Gate-Source Voltage . . . . .	-2
Gate Current . . . . .	10
Total Device Dissipation (Derate 1.7 mW/°C) . . . . .	300
Storage Temperature Range . . . . .	-65 to +20
Lead Temperature 1/16" from case for 10 sec . . . . .	30

### \*ELECTRICAL CHARACTERISTICS (25°C unless otherwise specified)

Characteristic	2N5397			
	Test Conditions	Min	Max	Unit
$I_{GSS}$ Gate Reverse Current	$V_{GS} = -15 \text{ V}, 25^\circ\text{C}$		-0.1	nA
	$V_{DS} = 0, 150^\circ\text{C}$		-0.1	μA
$BV_{GSS}$ Gate-Source Breakdown Voltage	$I_G = -1 \mu\text{A}, V_{DS} = 0$	-25		V
$V_P$ Gate-Source Punch-Off Voltage	$V_{DS} = 10 \text{ V}, I_D = 1 \text{ nA}$	-1	-6	V
$I_{DSS}$ Drain Current at Zero Gate Voltage †	$V_{DS} = 10 \text{ V}, V_{GS} = 0$	10	30	mA
$V_{GS(0)}$ Gate-Source Forward Voltage	$I_G = 1 \text{ mA}, V_{DS} = 0$		1	V
$g_{fs}$ Common-Source Forward Transconductance †	$V_{DS} = 10 \text{ V}, I_D = 10 \text{ mA}$	6000	10,000	μmho
	$f = 1 \text{ kHz}$		200	μmho
$g_{oss}$ Common-Source Output Conductance				
$C_{rss}$ Common-Source Reverse Transfer Capacitance	$V_{DG} = 10 \text{ V}, I_D = 10 \text{ mA}$		1.2	pF
	$f = 1 \text{ MHz}$		5	pF
$C_{iss}$ Common-Source Input Capacitance				

### \*HIGH FREQUENCY CHARACTERISTICS at 450 MHz (25°C)

Characteristic	Test Conditions	Min	Max	Unit	Test Conditions	Min	Max	Unit
$K_{iss}$ Common-Source Input Conductance	$V_{DG} = 10 \text{ V}, I_D = 10 \text{ mA}$		2000	μmho	$V_{DS} = 10 \text{ V}, V_{GS} = 0$		3000	μmho
			400	μmho			500	μmho
		5500	9000	μmho		5000	10,000	μmho
$K_{oss}$ Common-Source Output Conductance								
$K_{fs}$ Common-Source Forward Transconductance †								
$G_{pr}$ Common-Source Power Gain (neutralized)	$V_{DG} = 10 \text{ V}, I_D = 10 \text{ mA}$ See Page 4	15		dB				
NE Common-Source, Spot Noise Figure (neutralized)	$V_{DG} = 10 \text{ V}, I_D = 10 \text{ mA}$ See Page 4		3.5	dB				

\*JEDEC Registered Data

† Pulse test duration: 2 ms.

